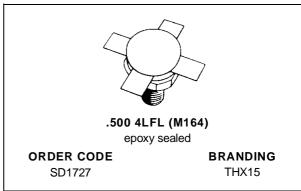


SD1727 (THX15)

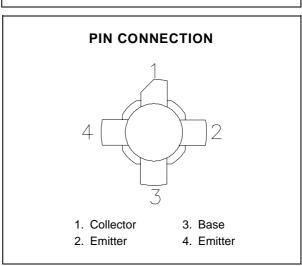
RF & MICROWAVE TRANSISTORS HF SSB APPLICATIONS

- OPTIMIZED FOR SSB
- 30 MHz
- 50 VOLTS
- IMD -30 dB
- COMMON EMITTER
- GOLD METALLIZATION
- P_{OUT} = 150 W PEP MIN. WITH 14 dB GAIN





The SD1727 is a 50 V epitaxial silicon NPN planar transistor designed primarily for SSB communications. This device utilizes emitter ballasting to achieve extreme ruggedness under severe operating conditions.



ABSOLUTE MAXIMUM RATINGS $(T_{case} = 25^{\circ}C)$

Symbol	Parameter	Value	Unit
V _{CBO}	Collector-Base Voltage	110	V
V _{CEO}	Collector-Emitter Voltage	55	V
V_{EBO}	Emitter-Base Voltage	4.0	V
Ic	Device Current	10	Α
P _{DISS}	Power Dissipation	233	W
TJ	Junction Temperature	+200	°C
T _{STG}	Storage Temperature	- 65 to +150	°C

THERMAL DATA

_								
	R _{TH(j-c)}	Junction-Case Thermal Resistance	0.75	°C/W				

November 1992 1/7

SD1727 (THX15)

ELECTRICAL SPECIFICATIONS $(T_{case} = 25^{\circ}C)$

STATIC

Cumbal	Test Conditions	Value			Unit		
Symbol	rest conditions		Min.	Тур.	Max.	Onit	
ВУсво	I _C = 100mA	$I_E = 0mA$		110		_	V
BVces	I _C = 100mA	$V_{BE} = 0V$		110	_	_	V
BVCEO	I _C = 100mA	$I_B = 0mA$		55	_	_	V
BV _{EBO}	I _E = 10mA	I _C = 0mA		4.0	_	_	V
ICEO	V _{CE} = 30V	I _E = 0mA		_	_	5	mA
Ices	V _{CE} = 60V	I _E = 0mA		_	_	5	mA
h _{FE}	V _{CE} = 6V	I _C = 1.4A		18	_	43.5	_

DYNAMIC

Symbol	Test Conditions		Value			Unit	
Syllibol	rest Conditions			Min.	Тур.	Max.	Unit
Pout	f = 30 MHz	$V_{CE} = 50 \text{ V}$	$I_{CQ} = 100 \text{mA}$	150	_	_	W
G _P *	Pout = 150 W PEP	$V_{CE} = 50 \text{ V}$	$I_{CQ} = 100 \text{mA}$	14	_	_	dB
IMD*	Pout = 150 W PEP	$V_{CE} = 50 V$	$I_{CQ} = 100 \text{mA}$	_	_	-30	dBc
ης*	Pout = 150 W PEP	V _{CE} = 50 V	I _{CQ} = 100mA	37	_	_	%
Сов	f = 1 MHz	V _{CB} = 50 V		_	_	220	pF

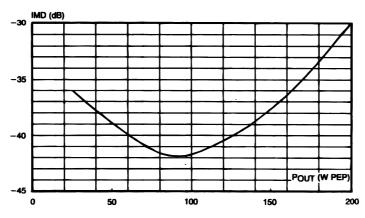
Note: The SD1727 is also usable in Class A at 40 V. Typical performance is:

 $P_{OUT} = 30 \text{ W PEP}, G_P = 14 \text{ dB}, IMD = -40 \text{dBc}$

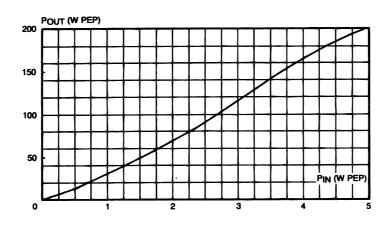
^{*} $f_1 = 30.00 \text{ MHz}; f_2 = 30.001 \text{ MHz}$

TYPICAL PERFORMANCE

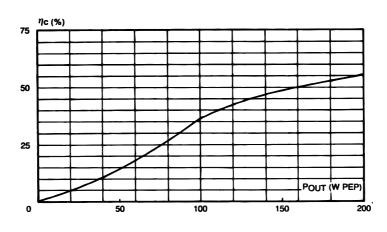




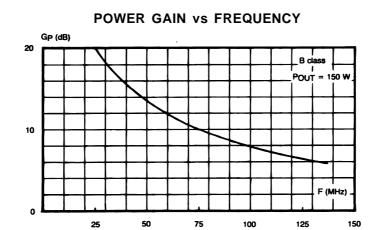
POWER OUTPUT PEP vs POWER INPUT



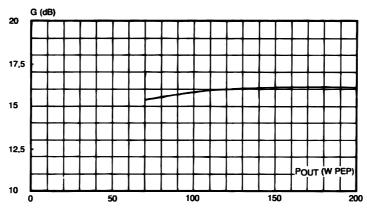
COLLECTOR EFFICIENCY vs POWER OUTPUT PEP



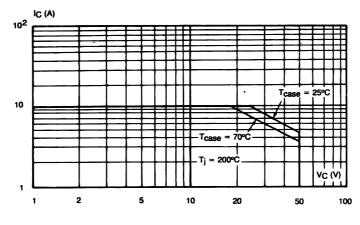
TYPICAL PERFORMANCE (cont'd)



POWER GAIN vs POWER OUTPUT PEP

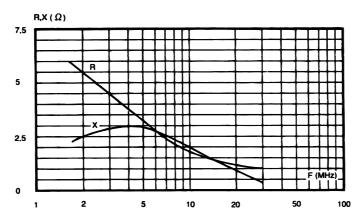


SAFE OPERATING AREA

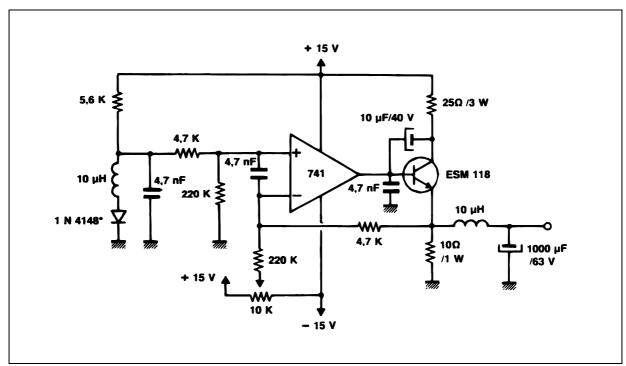


IMPEDANCE DATA

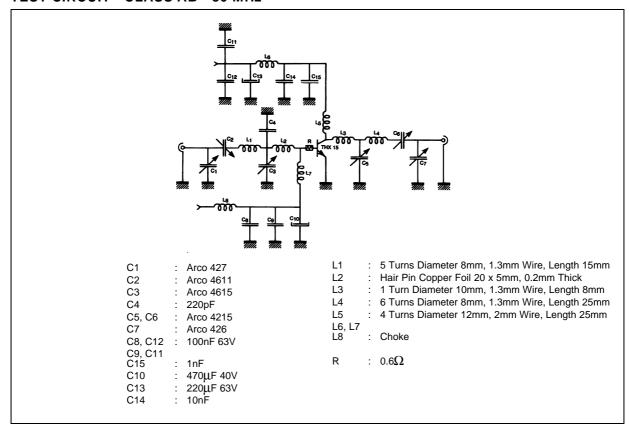
TYPICAL INPUT IMPEDANCE



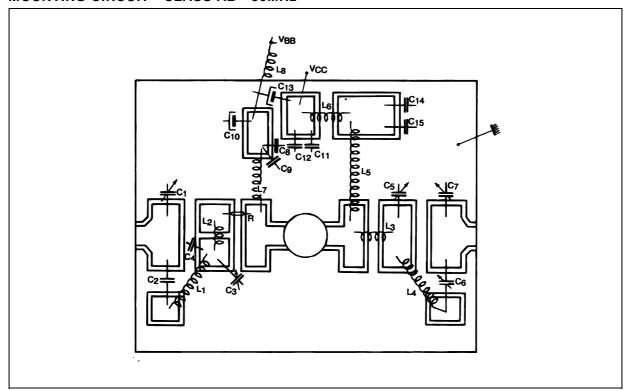
BIAS CRCUIT



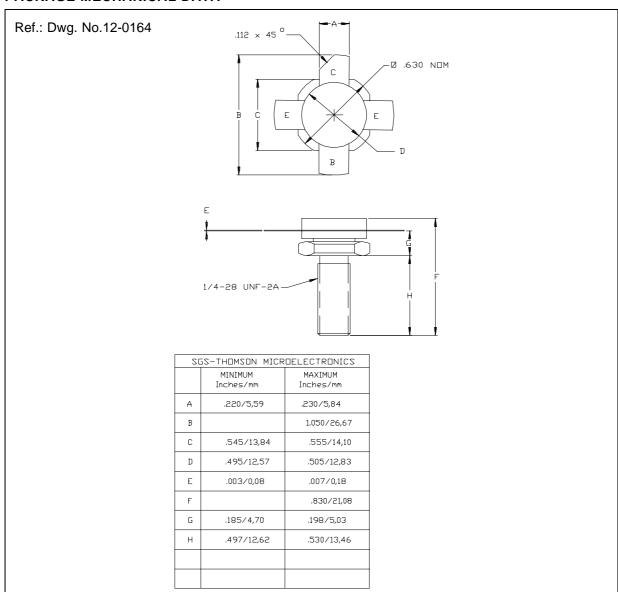
TEST CIRCUIT - CLASS AB - 30 MHz



MOUNTING CIRCUIT - CLASS AB - 30MHz



PACKAGE MECHANICAL DATA



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